

## Special Issue

# Advances in Image Processing, Analysis and Recognition Technology

### Message from the Guest Editor

The aim of this Special Issue on “Advances in Image Processing, Analysis and Recognition Technology” is to give the researchers the opportunity to provide new trends, latest achievements and research directions as well as present their current work on the important problem of image processing, analysis and recognition. Potential topics of interest for this Special Issue include (but are not limited) the following areas:

- Image acquisition
- Image quality analysis
- Image filtering, restoration and enhancement
- Image segmentation
- Multispectral image processing
- Hardware and architectures for image processing
- Image databases
- Image retrieval and indexing
- Image compression
- Mathematical methods in image processing, analysis and representation
- Pattern recognition algorithms applied for images
- Digital watermarking
- Digital photography
- Practical applications of image processing, analysis and recognition algorithms in medicine, surveillance, biometrics, document analysis, multimedia, intelligent transportation systems, stereo vision, remote sensing, computer vision, robotics, etc.

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### Guest Editor

Dr. Dariusz Frejlichowski

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### Deadline for manuscript submissions

closed (31 July 2020)



## Applied Sciences

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## About the Journal

### Message from the Editor-in-Chief

As the world of science becomes ever more specialized, researchers may lose themselves in the deep forest of the ever increasing number of subfields being created. This open access journal *Applied Sciences* has been started to link these subfields, so researchers can cut through the forest and see the surrounding, or quite distant fields and subfields to help develop his/her own research even further with the aid of this multi-dimensional network.

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### Editor-in-Chief

Prof. Dr. Giulio Nicola Cerullo  
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